Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/604,120	ARMAGOST ET AL.	
Examiner	Art Unit	
Tianjie Chen	2627	

SEARCHED					
Class	Subclass	Date	Examiner		
Updated		6/13/2006	TJ		

INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner	

SEAR (INCLUDING S	CH NOT EARCH S	ES STRATEGY	·)
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